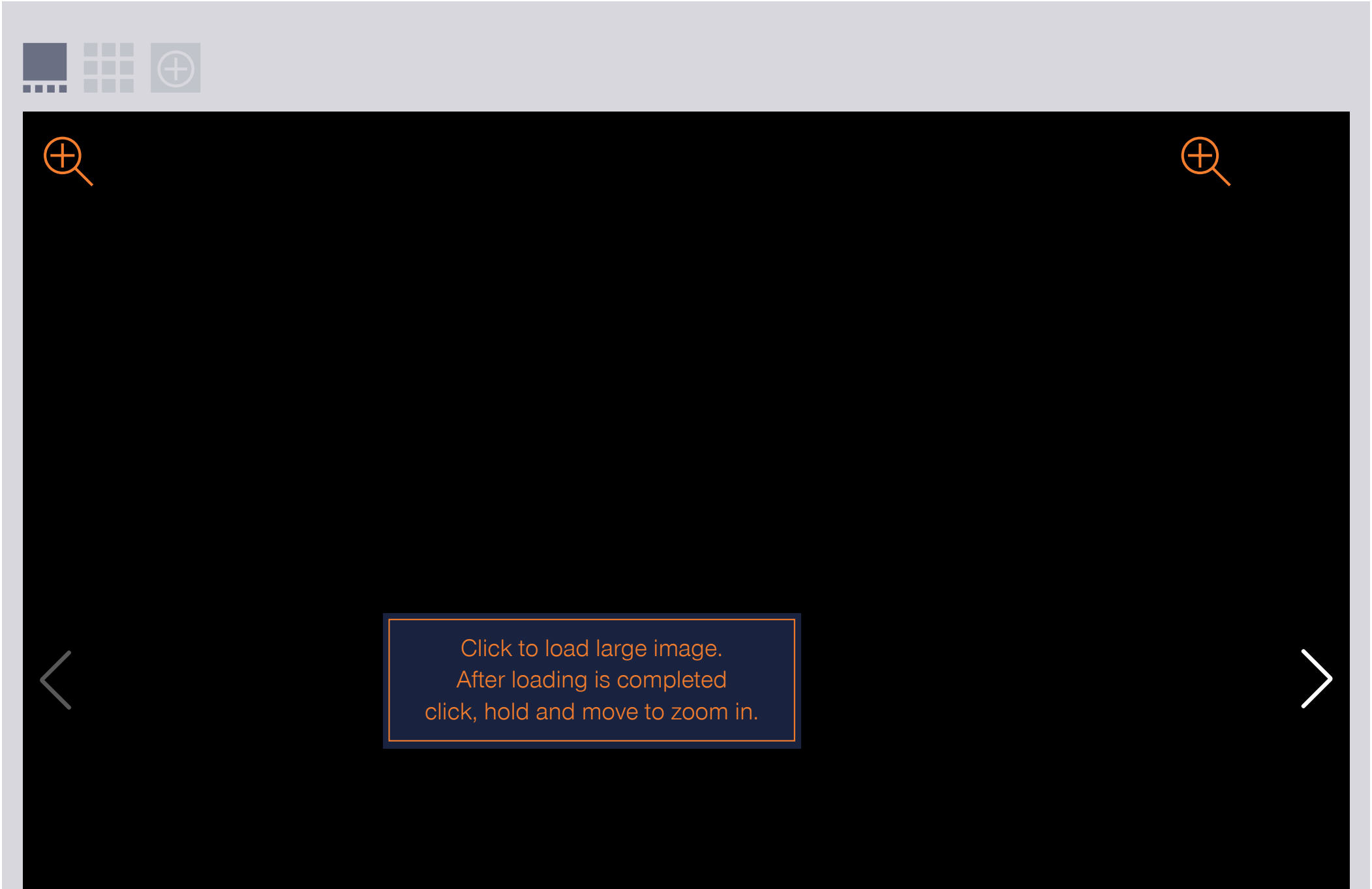


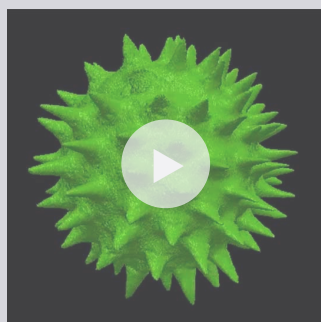
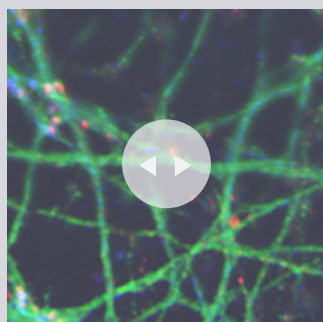
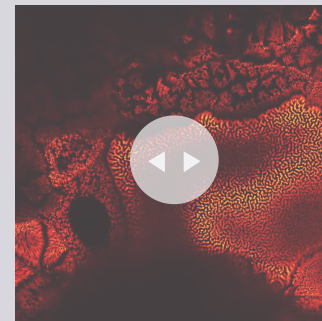
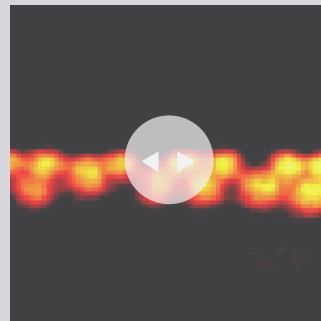
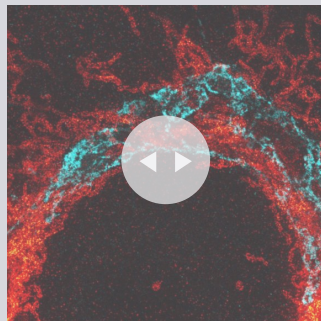
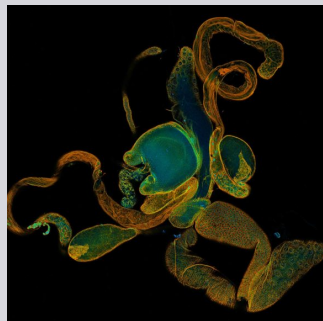
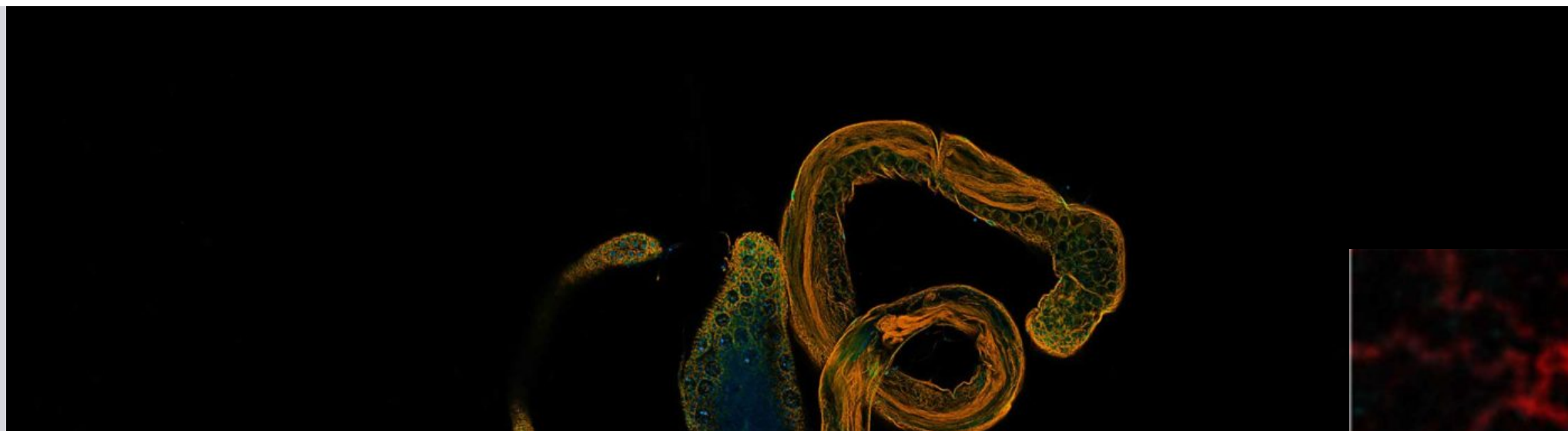


FACILITY

when every detail matters

Our *FACILITY* platform offers you a workhorse instrument that boasts top-of-the-line superresolution STED and confocal imaging. It combines cutting-edge microscopy with unprecedented ease-of-use. Our software allows beginners to intuitively arrive at a top-notch image within three clicks, while also giving experts full control over the instrument. Microscopy has never felt better.





Description

Tiled and stitched image of drosophila testis. Sample by J. Rehman.

FAQ 32

“What’s “facility” about *FACILITY* line?”

[Watch >](#)

FACILITY
best for imaging

Software
sensational

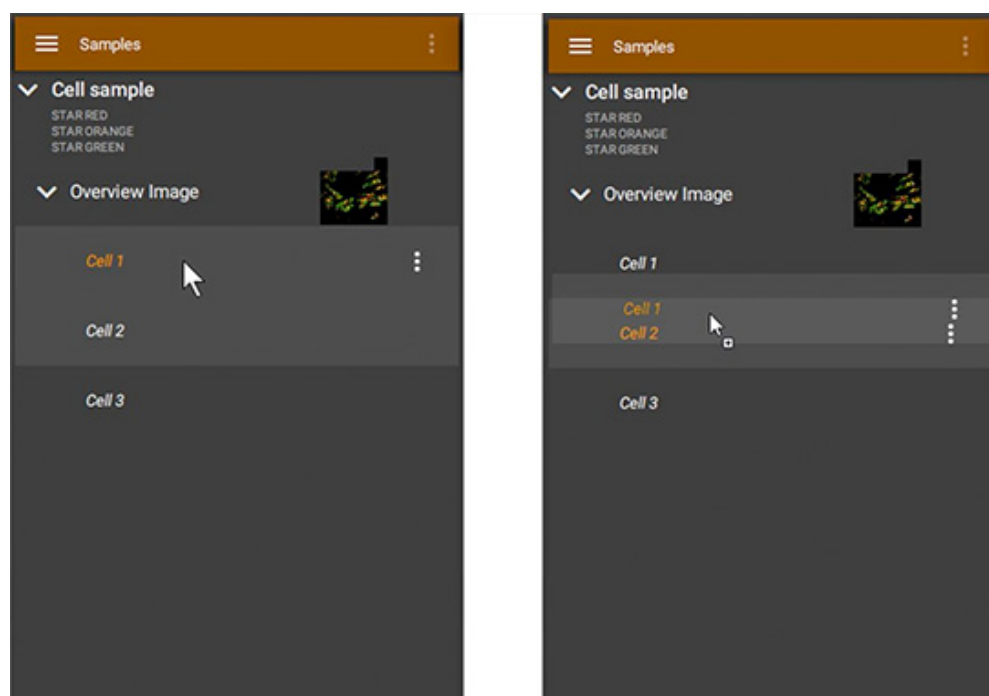
FAQ 12

“Does *abberior* offer live time imaging?”

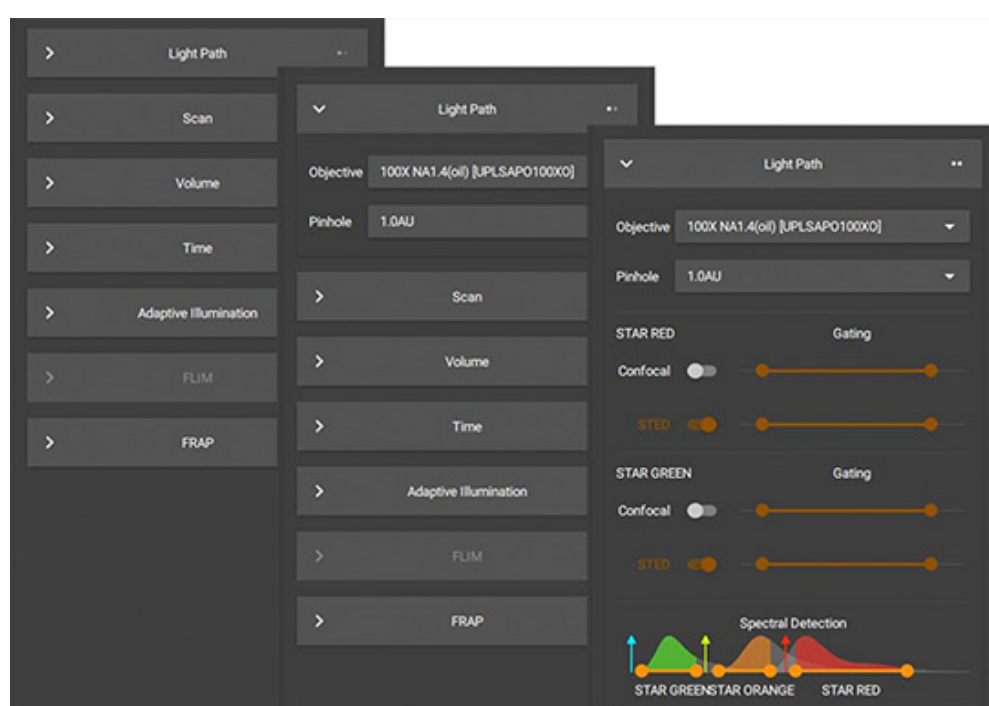
[Watch >](#)

Our *FACILITY* system is a truly cutting-edge micro- and nanoscope that is incredibly easy to use. It combines advanced features for high-end confocal and superresolution imaging with foolproof operation. [ADAPTIVE ILLUMINATION](#) (*DYMIN*, *RESCUE*, *MINFIELD*), [Adaptive Optics](#), [EASY3D](#) STED, confocal & STED [autofocus](#), spectral [RAINBOW](#) detection, and full [AUTOALIGNMENT](#).

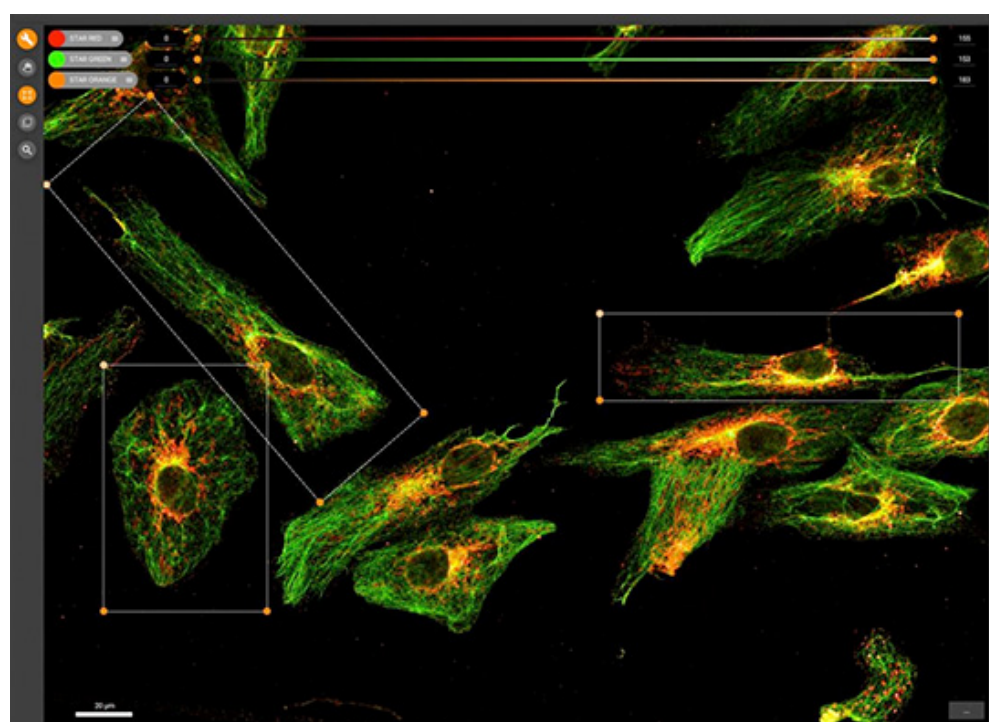
Our new software was designed from scratch to furnish a user interface that allows beginners to intuitively arrive at a top-notch STED image within three clicks, while it triggers a steep learning curve and allows expert users full control over the instrument. The unprecedented workflow outshines everything you have seen before.



Tree view supports drag & drop



Escalations follow user levels



Free selection of ROIs

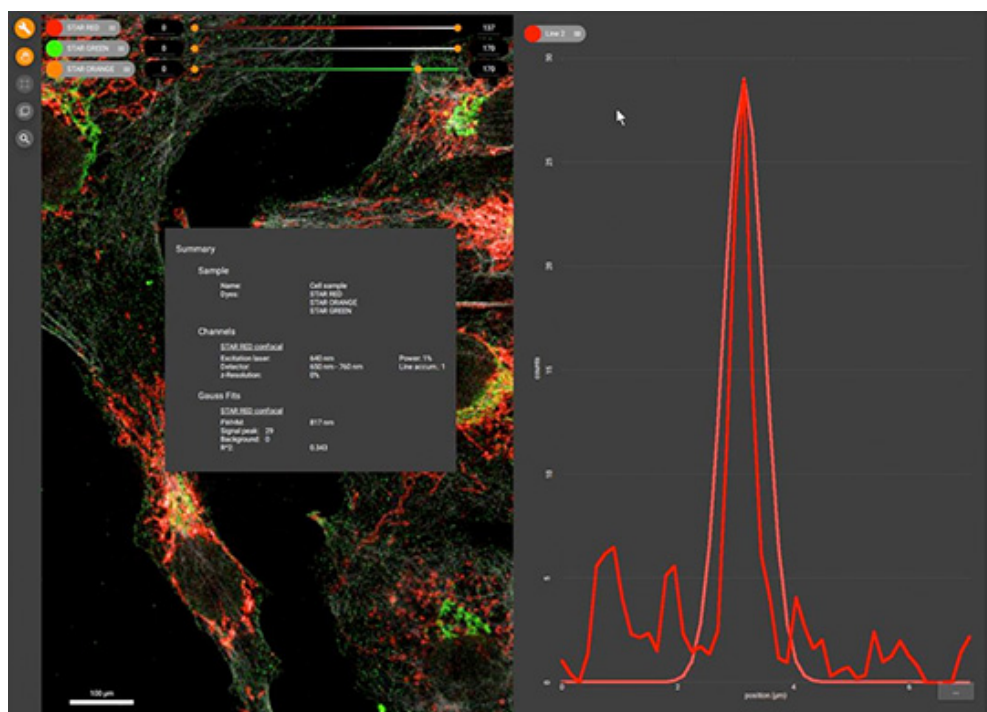
All images are grouped hierarchically in a “tree view”, where context between measurements is kept from the sample level over large overviews down to final images. This way, STED and confocal measurements can always be spatially related to the greater environment of the sample, and you can switch between different modes at the push of a button. There is no need to zoom out to find a good area, followed by zooming in, adjusting settings such as pixel size and line frequency, taking an image, zooming out again, re-adjusting pixel size... all this is one click on the *FACILITY*. On top, the tree view supports drag and drop (right) to transfer settings to other images. Once you have found good settings for your sample, they can be applied lightning fast to all images, in this case from a measured “Cell 1” to a new region of interest called “Cell 2”

The *FACILITY* software supports new and advanced users alike. After entering the dyes that are in your sample, the machine knows everything about excitation wavelengths, detection bands, STED settings, etc. From there, you simply select a region you want to image and the first scan will give you a good superresolution measurement. After this, it’s a breeze to optimize settings.

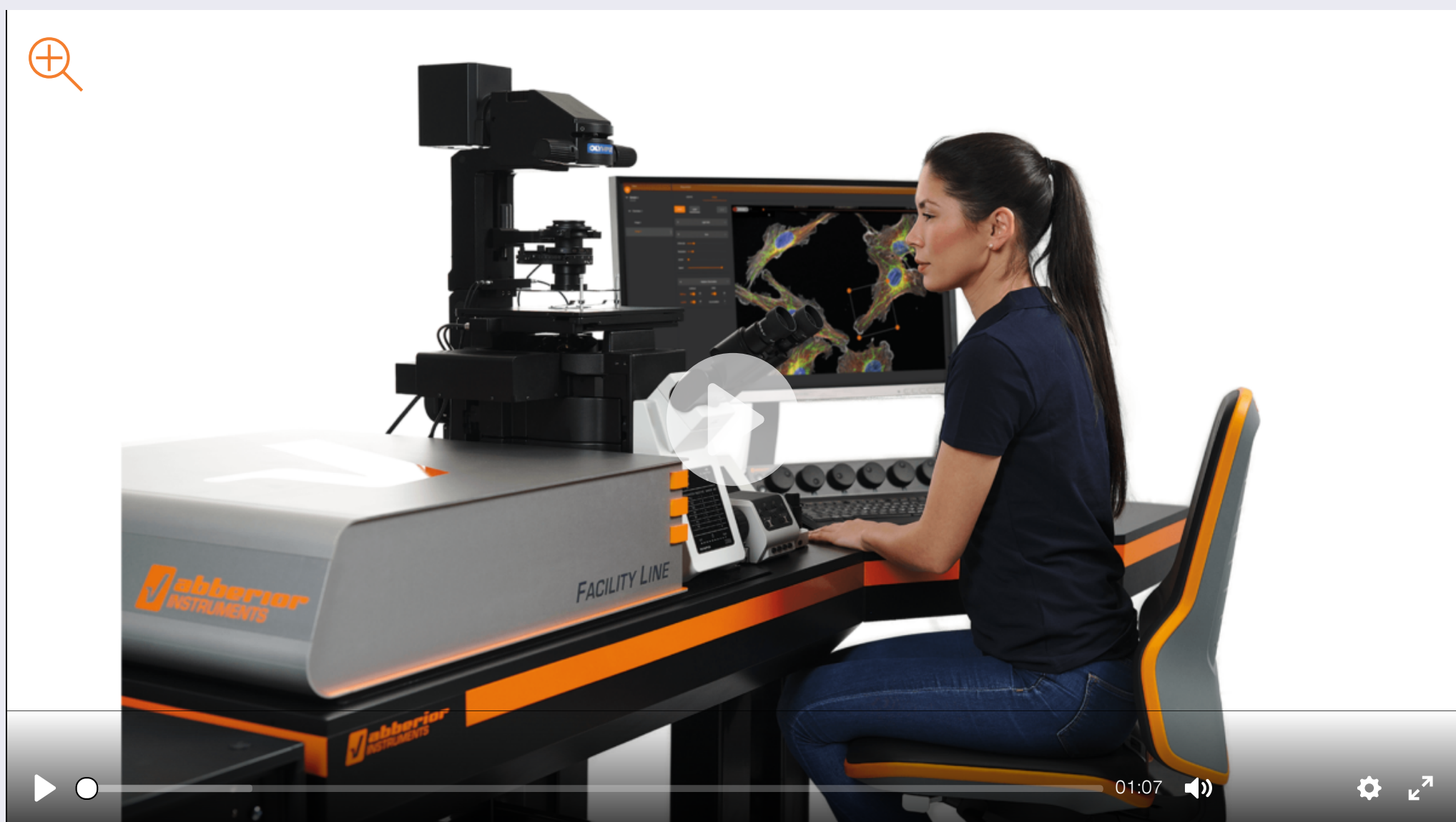
All functions are grouped in convenient tabs that can be escalated to adapt to different user levels. In the example above, Light Path controls are unfolded, first to show basic objective and pinhole controls, while a more advanced user can move one escalation higher to manipulate gating and detection settings. This way, you only see what you need in the moment, cluttered screens with hundreds of buttons are avoided, and new users don’t feel overwhelmed, while advanced users are in full control.

The *FACILITY* software allows tiled scans, and in every scan you can select an arbitrary number of regions of interests (ROIs, corresponding to items in the tree view, see above). Every ROI itself can serve as an overview again, meaning that you can easily climb down from sample level overviews to detailed superresolution images, while spatial context is saved at all times. Of course, the *FACILITY* supports arbitrarily rotated ROIs, even in STED mode!

After you’ve acquired your images, our software offers powerful analysis features, such as measurements, plus, images can be sent to Huygens SVI for stitching, deconvolution, and rendering.



Powerful analytical tools, support of Hyugens SVI



What others say

*Prof. Michelle Peckham
University of Leeds
Leeds, United Kingdom*

“Like the *STEDYCON*, the *FACILITY* line is very easy to use and it will work very well



Dr. Antonio Virgilio Failla
Head of the UKE Microscopy
Imaging Facility
Hamburg, Germany

“The *FACILITY* line is the best way to produce world class scientific results. It is driven by a fantastic user interface and I would recommend it to every imaging facility.”



in an imaging facility.”



Dr. Hans-Ulrich Fried
Head of the Light
Microscope Facility, DZNE
Bonn, Germany

“The *FACILITY* line is an impressive superresolution and confocal microscope combining ease of use with cutting edge technology. The usage of intelligent illumination schemes allows live-cell recordings with high-resolution STED at an extraordinary low light level.”



Prof. Christian Eggeling
Friedrich-Schiller-Universität
Jena, Germany, and
University of Oxford, United
Kingdom

“The *FACILITY* line is a highly flexible turn-key instrument that combines extremely powerful superresolution imaging, including unique features such as adaptive optics, and intelligent scanning schemes, with a fantastic user interface.”

- Advanced confocal and superresolution features (EASY3D, tiling/stitching, multi-ROI recordings, adaptive illumination, full autoalignment, ...)
- Unprecedented workflow

***Powerful performance
combined with sublime
useability***

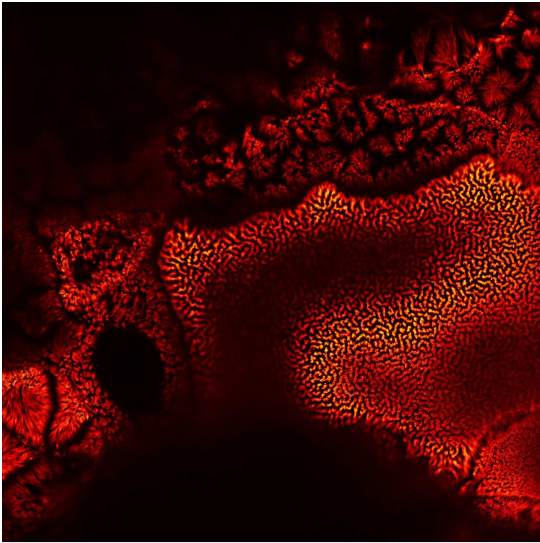


Dr. Andreas Schönle
Physicist, Co-Founder and passionate Photon Hunter

“Why do we usually recommend APDs in our microscopes and why aren’t we worried about the supposedly lower dynamic range?”

Dr. Andreas Schönle

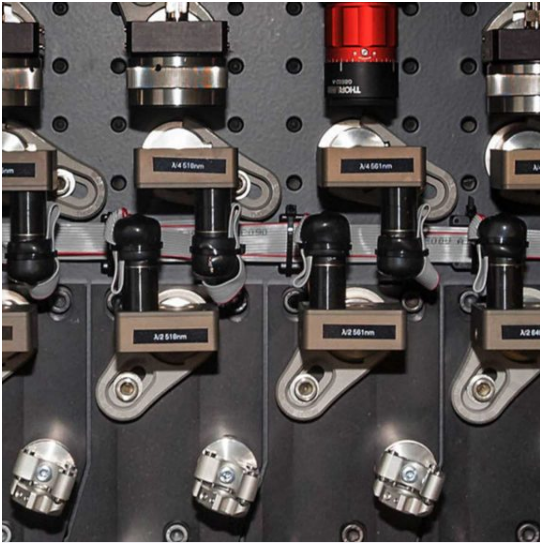
[Details >](#)



MATRIX Detector

Many eyes see more than one. The MATRIX detector drastically improves signal-to-background ratio, resolution, and dynamic range.

[Details >](#)



Expert Devices

Expert devices expand your microscope and turn it into a powerful instrument ready to take up any imaging challenge.

[Details >](#)



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